

IRF9Z34NL-VB Datasheet

P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^a	Q _g (Typ.)		
- 60	0.0160at V _{GS} = - 10 V	- 53	76 nC		
- 60	0.0200 at V_{GS} = - 4.5 V	- 42	70110		

FEATURES

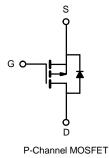
- Trench Power MOSFET
- 100 % UIS Tested

APPLICATIONS

Load Switch







Parameter		Symbol	Limit	Unit
Drain-Source Voltage		V _{DS}	- 60	V
Gate-Source Voltage		V _{GS}	± 20	
	T _C = 25 °C		- 53 ^a	
Continuous Droin Current (T = 150 °C)	T _C = 70 °C		- 46.8	
Continuous Drain Current ($T_J = 150 \text{ °C}$)	T _A = 25 °C	I _D	9.2 ^b	A
	T _A = 70 °C		- 8.1 ^b	A
Pulsed Drain Current		I _{DM}	- 150	
Avalanche Current Pulse	che Current Pulse L = 0.1 mH		- 45	
Single Pulse Avalanche Energy	L = 0.1 MH	E _{AS}	101	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C	L.	69 ^a	A
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	2.1 ^b	A
	T _C = 25 °C		104.2 ^a	
Maximum Power Dissipation	T _C = 70 °C	Р	66.7 ^a	w
	T _A = 25 °C	P _D	3.1 ^b	vv
	T _A = 70 °C		2 ^b	
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^b	Steady State	R _{thJA}	33	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.98	1.2	C/VV	

Notes:

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a. Based on $T_C = 25 \ ^{\circ}C$.

b. Surface mounted on 1" x 1" FR4 board.

Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static	Symbol	Test conditions	IVIII.	тур.	IVIAX.	Onit	
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = - 250 μA	- 60			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$			68			
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I _D = - 250 μA		- 5.2		mV/°0	
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} = V _{GS} , I _D = - 250 μA	- 1	0.2	- 3	V	
Gate-Source Leakage		$V_{DS} = 0 V, V_{GS} = \pm 20 V$	·		± 100	nA	
Zero Gate Voltage Drain Current	I _{DSS}	$V_{\rm DS} = -60 \text{ V}, \text{ V}_{\rm GS} = 0 \text{ V}$		- 1			
		$V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}$ $V_{DS} = -60 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55 \text{ °C}$			- 10	μA	
On-State Drain Current ^a	I _{D(on)}	$V_{DS} = -5 V, V_{GS} = -10 V$	- 120			A	
	D (on)	V _{GS} = - 10 V, I _D = - 30 A	-	0.0160		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = -4.5 \text{ V}, I_D = -20 \text{ A}$		0.0200			
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 50 A	20			S	
Dynamic ^b						<u> </u>	
Input Capacitance	C _{iss}			3500			
Output Capacitance	C _{oss}	V _{DS} = - 25 V, V _{GS} = 0 V, f = 1 MHz		390		pF	
Reverse Transfer Capacitance	C _{rss}			290			
Total Gate Charge	Qg	V _{DS} = - 30 V, V _{GS} = - 10 V, I _D = - 55 A		76	115	1	
				38	60		
Gate-Source Charge	Q _{gs}	$V_{DS} = -30$ V, $V_{GS} = -4.5$ V, $I_{D} = -55$ A		16		- nC	
Gate-Drain Charge	Q _{gd}			19			
Gate Resistance	Rg	f = 1 MHz		5.2		Ω	
Turn-On Delay Time	t _{d(on)}			10	15		
Rise Time	t _r	V_{DD} = - 2 V, R_L = 2 Ω		7	15	- ns	
Turn-Off Delay Time	t _{d(off)}	I_D \cong - 10 A, V_{GEN} = - 10 V, R_g = 1 Ω		70	110		
Fall Time	t _f			40	60		
Drain-Source Body Diode Characteristics	5						
Continuous Source-Drain Diode Current	ا _S	T _C = 25 °C			- 69	^	
Pulse Diode Forward Current ^a	I _{SM}				- 150	— A	
Body Diode Voltage	V _{SD}	I _S = - 30 A		- 1	- 1.5	V	
Body Diode Reverse Recovery Time	t _{rr}			45	68	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	L = 50 A di/dt = 100 A/up T = 25 °C		59	120	nC	
Reverse Recovery Fall Time	ta	I _F = - 50 A, di/dt = 100 A/μs, T _J = 25 °C		29			
Reverse Recovery Rise Time	t _b	-		16		ns	

Notes:

a. Pulse test; pulse width \leq 300 $\mu s,$ duty cycle \leq 2 %.

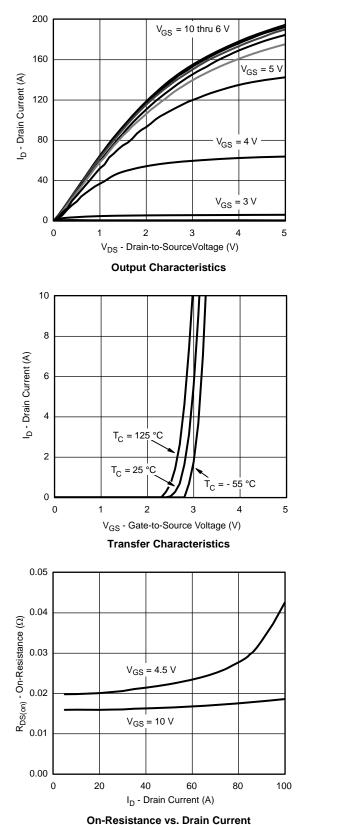
b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

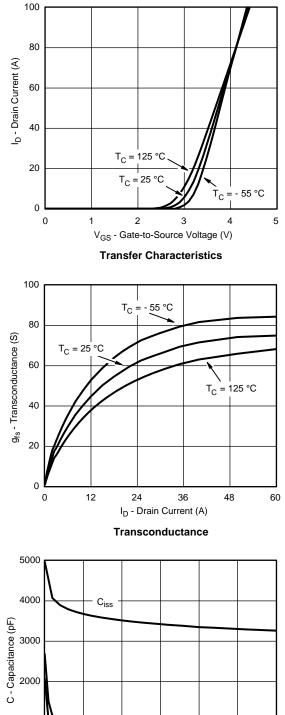
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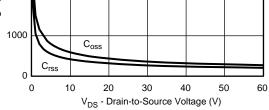
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TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





Capacitance



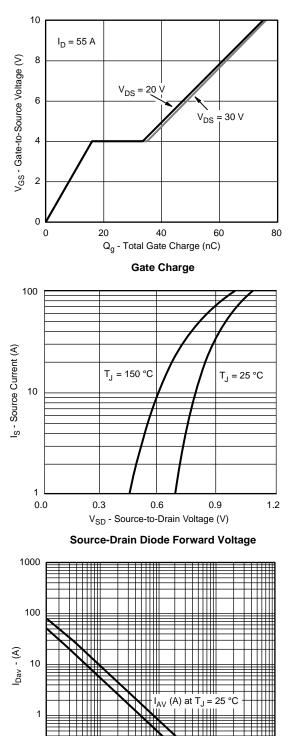
150

10 V V_{GS} =

 $V_{GS} = 4.5 V$

100

125



 I_{AV} (A) at T_{J} = 150

0.001

11111

0.01

T_{in} - (s)

Single Pulse Avalanche Current Capability vs. Time

0.1

1

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

On-Resistance vs. Gate-to-Source Voltage 0.10 I_D = 20 A 0.08 0.06 0.04 T_J = 150 °C

25

50

T_J - Junction Temperature (°C)

75

0

2.0

1.7

1.4

1.1

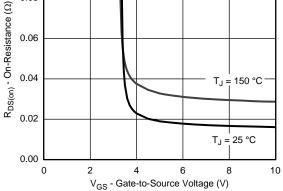
0.8

0.5

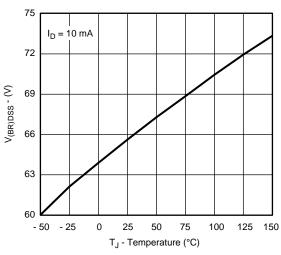
- 50 - 25

R_{DS(on)} - On-Resistance (Normalized)

I_D = 20 A



On-Resistance vs. Gate-to-Source Voltage

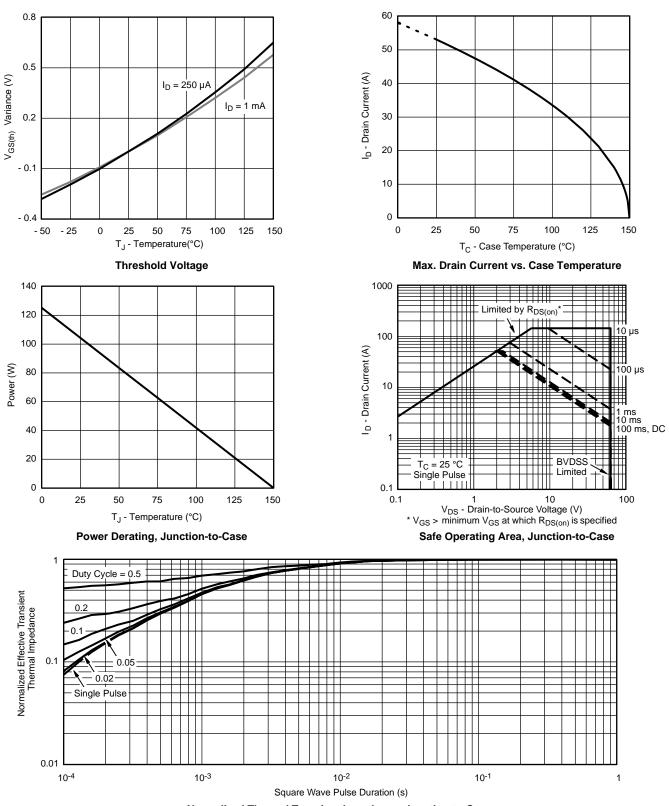


Drain-Source Breakdown Voltage vs. Junction Temperature

0.1

0.0001



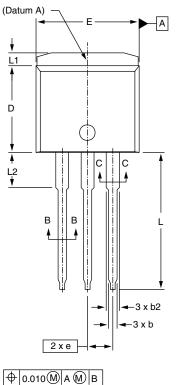


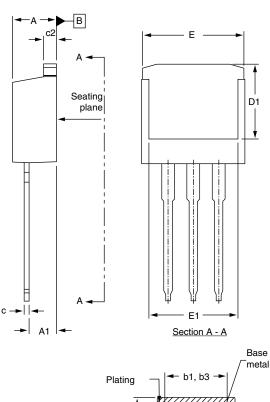
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

Normalized Thermal Transient Impedance, Junction-to-Case



I²PAK (TO-262) (HIGH VOLTAGE)





ment

MILLIMETERS

MAX.

4.83

3.02

0.99

0.89

1.78

1.73

0.74

0.58

Lead tip

MIN.

4.06

2.03

0.51

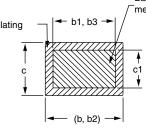
0.51

1.14

1.14

0.38

0.38



Section B - B and C - C Scale: None

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D	8.38	9.65	0.330	0.380
D1	6.86	-	0.270	-
E	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
L	13.46	14.10	0.530	0.555
L1	-	1.65	-	0.065
L2	3.56	3.71	0.140	0.146

c2	1.14	1.65				
ECN: S-82442-Rev. A, 27-Oct-08 DWG: 5977						

Notes

DIM.

А

A1

b

b1

b2

b3

С

c1

1. Dimensioning and tolerancing per ASME Y14.5M-1994.

2. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm per side. These dimensions are measured at the outmost extremes of the plastic body.

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INCHES

MAX.

0.190

0.119

0.039

0.035

0.070

0.068

0.029

0.023

0.065

MIN.

0.160

0.080

0.020

0.020

0.045

0.045

0.015

0.015

0.045

3. Thermal pad contour optional within dimension E, L1, D1, and E1.

4. Dimension b1 and c1 apply to base metal only.



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